Atomic Force Microscopy

Atomic Force Microscope at Center for Nanoscience & Nanotechnology

Atomic force microscope is a type of scanning probe microscopy used for determining surface topography at high resolution. The information in AFM is gathered by touching the surface with a mechanical probe or tip with a radius of the order of nanometer range. The tip is held several nanometers above the surface using a feedback mechanism that measures surface–tip interactions on the scale of nanoNewtons force. Variations in tip height are recorded while the tip is scanned repeatedly across the sample, producing a topographic 2D and 3D image of the thin film on a solid sample surface.

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